

<b>Notice of References Cited</b>	Application/Control No. 10/715,737	Applicant(s)/Patent Under Reexamination JAISWAL ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0167338	09-2003	Hare et al.	709/236
*	B	US-2002/0044567	04-2002	Voit et al.	370/467
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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